



FET-C X-ray Option

The FET-C X-ray Option adds a fully integrated x-ray inspection station to the FET-C series machines. Internal characteristics such as powder presence, ground pin location, charge sleeve orientation and feature detection may be provided.

Versatile, reliable, x-ray analysis is provided with this FET-C option. Fully integrated into the FET-C software application, the x-ray test may be enabled or disabled and the specific parameters used for the x-ray test associated with each individual part number. The test results for all tests, including the x-ray test, are archived automatically.

All defective parts are removed from the conveyor into assignable reject bins. Realtime information is presented on the operator screens.



A variety of x-ray sources are available, including those from Hamamatsu (80KV) and KeveX (130KV). This high speed station may be specified with image archive (DVD-RAM) or hard disk storage for different requirements. A separate image monitor is provided for real-time image display during operation.

FET-C X-ray Option provides:

- Fully automated testing
- Automatic Defect Recognition
- High resolution camera
- Adjustable source voltage
- High reliability

